

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10586798	KANEKO ET AL.
Examiner		Art Unit
shih-wen hsieh		2861

SEARCHED

Class	Subclass	Date	Examiner
347	22-36,100,102, 104,106	9-1-08	SWH

SEARCH NOTES

Search Notes	Date	Examiner

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

	/shih-wen hsieh/ Primary Examiner, Art Unit 2861
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